Se	Se <i>arch Notes</i>			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/675,076	KARAOGUZ ET AL.
Examiner	Art Unit
John M. Frink	2142

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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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inventors + text	4/11/2007	JMF
subclass + text	4/11/2007	JMF
assignee + text	4/11/2007	JMF